

## Features

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology
- ★ 100% EAS Guaranteed

## Product Summary

**RoHS**

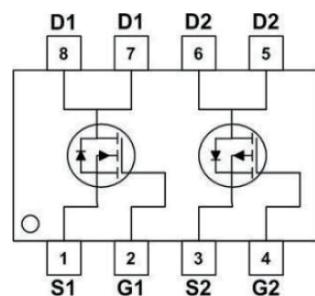
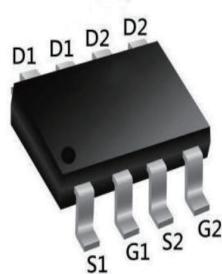
BVDSS	RDS(on)	ID
40V	17mΩ	8.5A
-40V	39mΩ	-7.5A

## Description

THE 4614 is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density , which provide excellent RDS(on) and gate charge for most of the synchronous buck converter applications .

THE 4614 meet the RoHS and Green Product requirement , 100% EAS guaranteed with full function reliability approved.

## SOP8 Pin Configuration



## Absolute Maximum Ratings

Symbol	Parameter		Max. N-Channel	Max. P-Channel	Units
V <sub>DSS</sub>	Drain-Source Voltage		40	-40	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	±20	V
I <sub>D</sub>	Continuous Drain Current	T <sub>A</sub> = 25°C	8.5	-7.5	A
		T <sub>A</sub> = 100°C	5.2	-3.9	A
I <sub>DM</sub>	Pulsed Drain Current <sup>note1</sup>		32	-24	A
E <sub>AS</sub>	Single Pulsed Avalanche Energy <sup>note2</sup>		13	17.6	mJ
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25°C	2	3.2	W
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient		62.5	39	°C/W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150		°C

Electrical Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise specified) N-Channel

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
<b>Off Characteristics</b>						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	40	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=40\text{V}, V_{GS}=0\text{V}$	-	-	1	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.5	2.5	V
$R_{DS(on)}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10\text{V}, I_D=8\text{A}$	-	17	22	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=5\text{A}$	-	25	35	$\text{m}\Omega$
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS}=20\text{V}, V_{GS}=0\text{V}, f=1.0\text{MHz}$	-	633	-	pF
$C_{oss}$	Output Capacitance		-	67	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	58	-	pF
$Q_g$	Total Gate Charge	$V_{DS}=20\text{V}, I_D=8\text{A}, V_{GS}=10\text{V}$	-	12	-	nC
$Q_{gs}$	Gate-Source Charge		-	3.2	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	3.1	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}= 20\text{V}, R_L=2.5\Omega$	-	4	-	ns
$t_r$	Turn-on Rise Time		-	3	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	15	-	ns
$t_f$	Turn-off Fall Time		-	2	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	8.5	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	32	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}, I_S= 8\text{A}$	-	-	1.2	V

## Note :

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2.EAS condition :  $T_J=25^\circ\text{C}, V_{DD}=20\text{V}, V_G=10\text{V}, L=0.5\text{mH}, R_g=25\Omega, I_{AS}=7.2\text{A}$  $T_J=25^\circ\text{C}, V_{DD}=-20\text{V}, V_G= -10\text{V}, L=0.5\text{mH}, R_g=25\Omega, I_{AS}=-8.4\text{A}$ 3.Pulse Test: Pulse Width $\leqslant 300\mu\text{s}$ , Duty Cycle $\leqslant 2\%$

Electrical Characteristics ( $T_J = 25^\circ C$  unless otherwise specified) P-Channel

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
<b>Off Characteristics</b>						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D = -250\mu A$	-40	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -40V, V_{GS}=0V$	-	-	-1	$\mu A$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D = -250\mu A$	-1	-1.6	-2.5	V
$R_{DS(on)}$ note3	Static Drain-Source on-Resistance	$V_{GS} = -10V, I_D = -6A$	-	39	53	$m\Omega$
		$V_{GS} = -4.5V, I_D = -4A$	-	58	81	$m\Omega$
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = -20V, V_{GS}=0V, f=1.0MHz$	-	860	-	pF
$C_{oss}$	Output Capacitance		-	87	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	70	-	pF
$Q_g$	Total Gate Charge	$V_{DS} = -20V, I_D = -6A, V_{GS} = -10V$	-	13	-	nC
$Q_{gs}$	Gate-Source Charge		-	3.8	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	3.1	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = -20V, R_L = 2.3\Omega$	-	7.5	-	ns
$t_r$	Turn-on Rise Time		-	5.5	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	19	-	ns
$t_f$	Turn-off Fall Time		-	7	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	-7.5	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-24	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS}=0V, I_S = -6A$	-	-	-1.2	V

Note :

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2.EAS condition :  $T_J=25^\circ C, V_{DD}=20V, V_G=10V, L=0.5mH, R_g=25\Omega, I_{AS}=7.2A$                    $T_J=25^\circ C, V_{DD}=-20V, V_G= -10V, L=0.5mH, R_g=25\Omega, I_{AS}=-8.4A$ 3.Pulse Test: Pulse Width $\leqslant 300\mu s$ , Duty Cycle $\leqslant 2\%$

### N-Channel Typical Performance Characteristics

Figure 1: Typical Output Characteristics

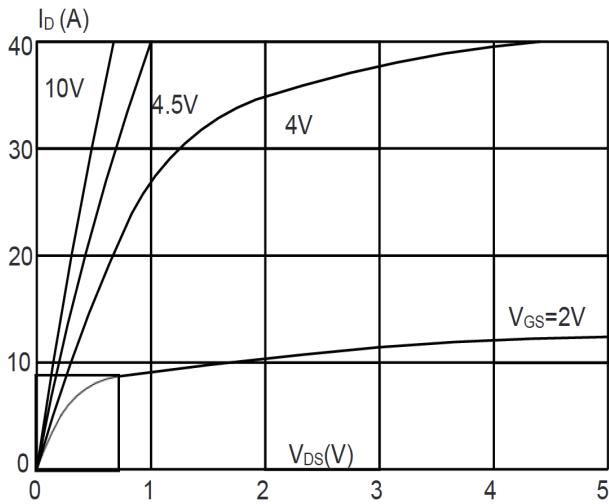


Figure 2: Typical Transfer Characteristics

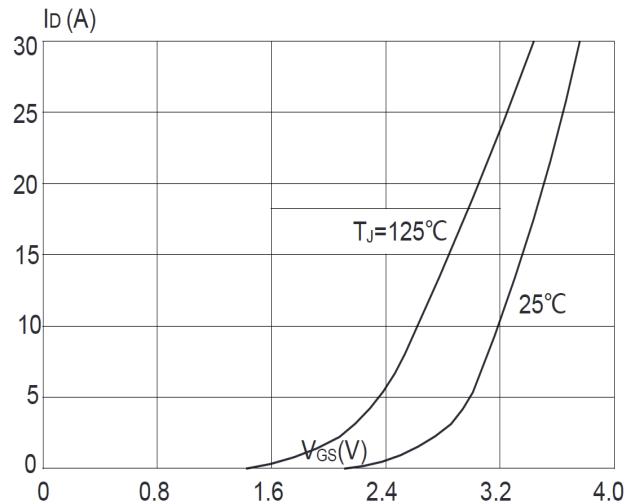


Figure 3: On-resistance vs. Drain Current

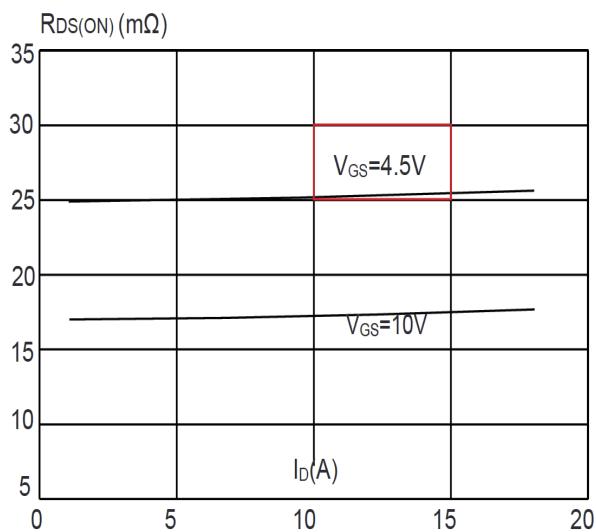


Figure 4: Body Diode Characteristics

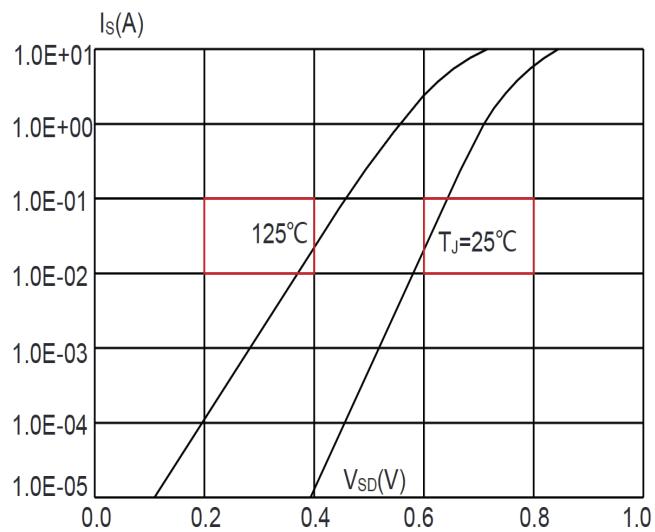


Figure 5: Gate Charge Characteristics

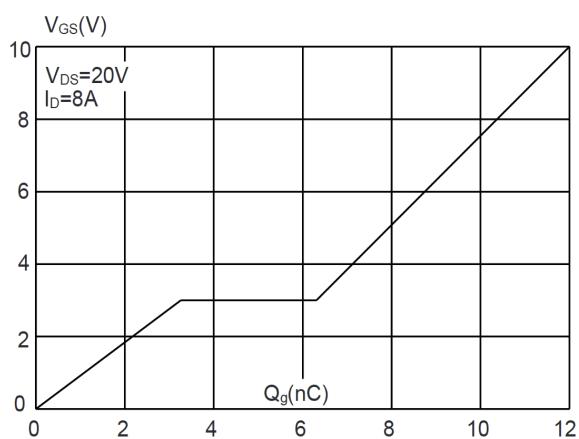
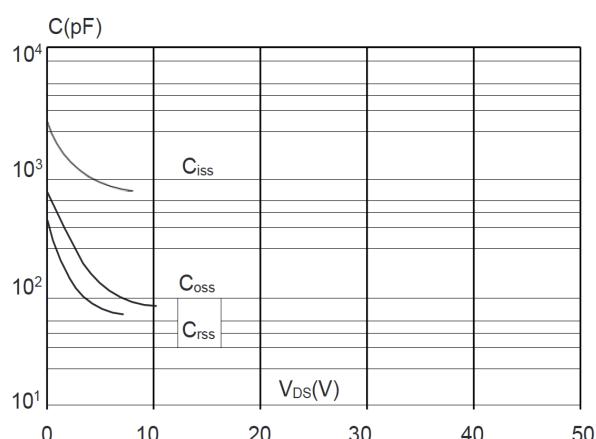
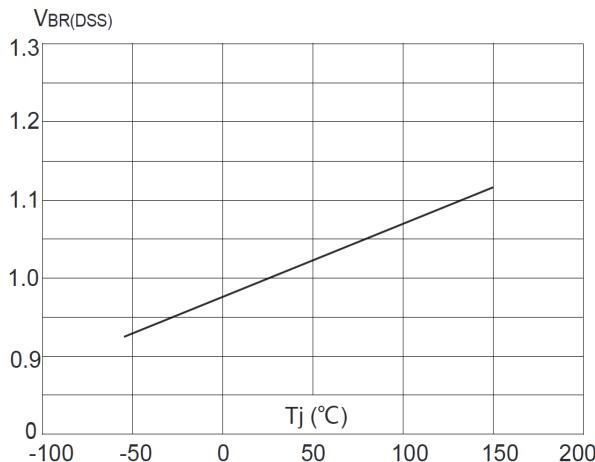


Figure 6: Capacitance Characteristics

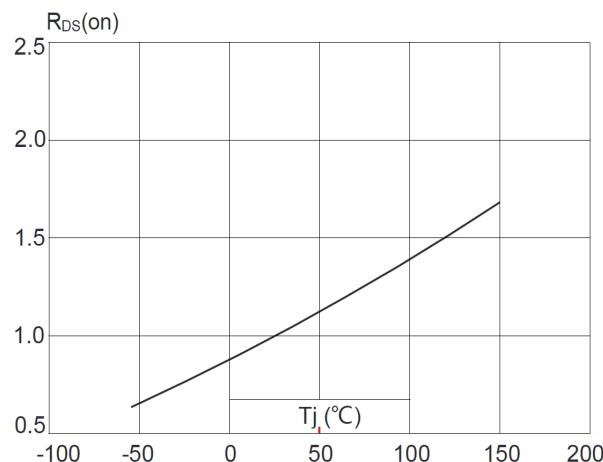


### N-Channel Typical Performance Characteristics

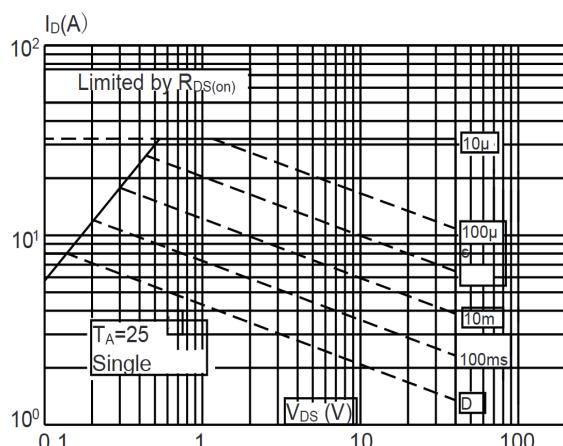
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**



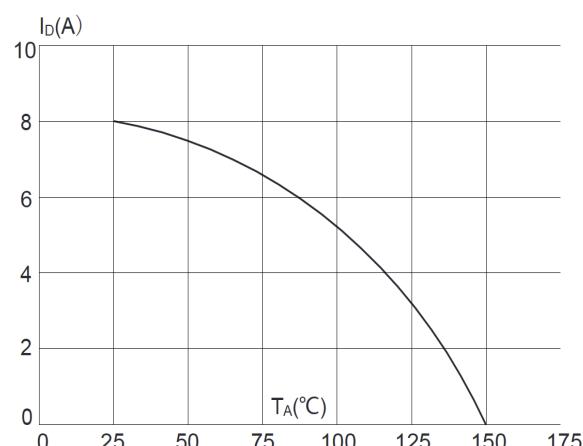
**Figure 8: Normalized on Resistance vs. Junction Temperature**



**Figure 9: Maximum Safe Operating Area**

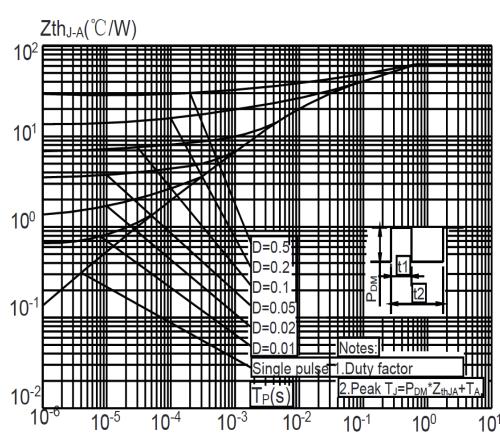


**Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature**



**Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient**

Transient Thermal Impedance, Junction-to-Ambient



### P-Channel Typical Performance Characteristics

Figure 1: Typical Output Characteristics

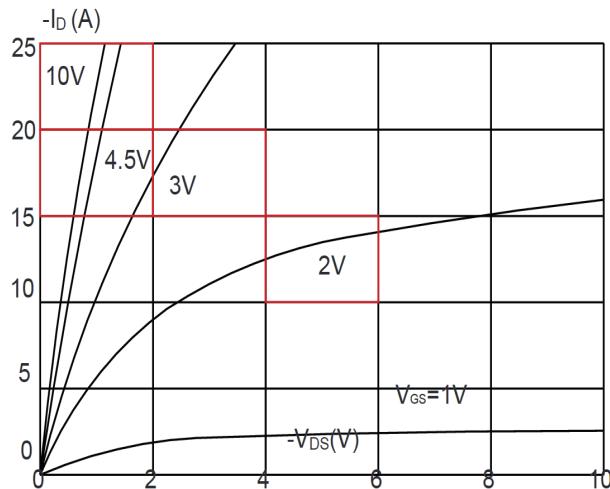


Figure 2: Typical Transfer Characteristics

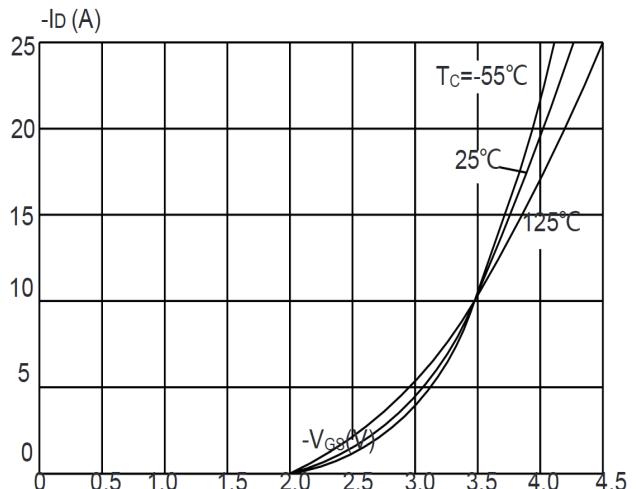


Figure 3: On-resistance vs. Drain Current

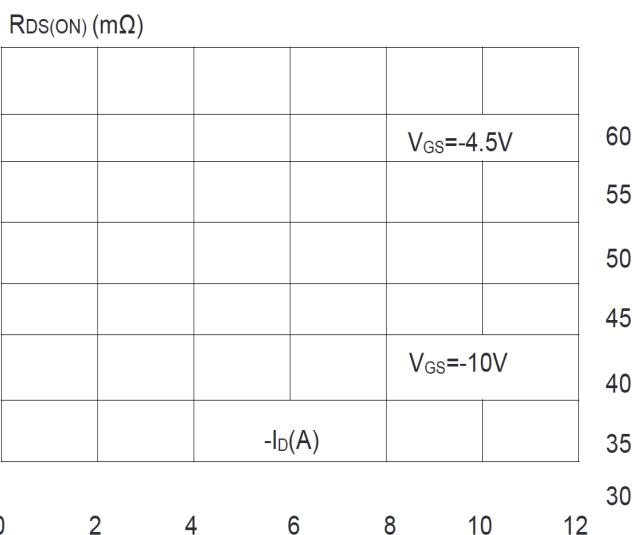


Figure 4: Body Diode Characteristics

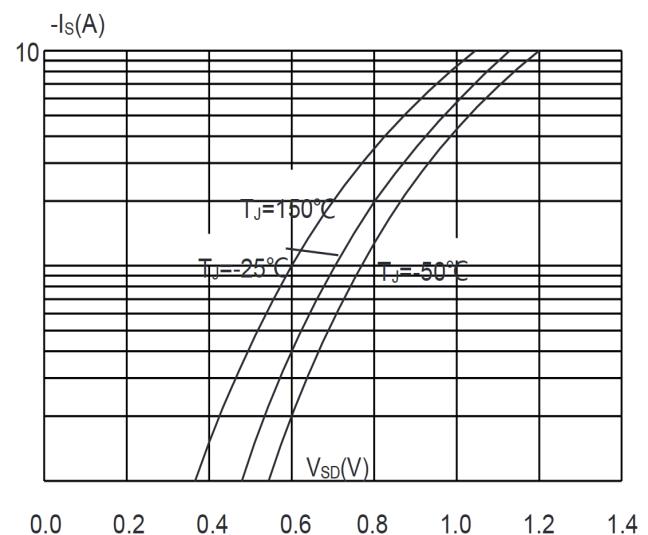


Figure 5: Gate Charge Characteristics

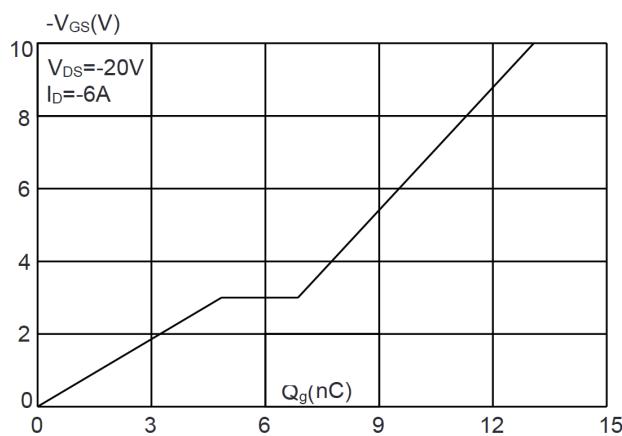
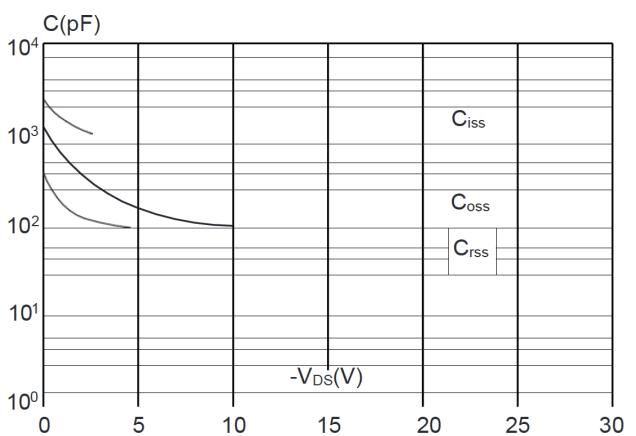
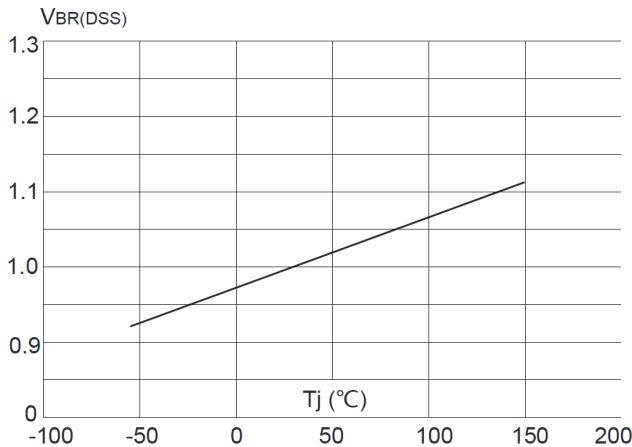


Figure 6: Capacitance Characteristics

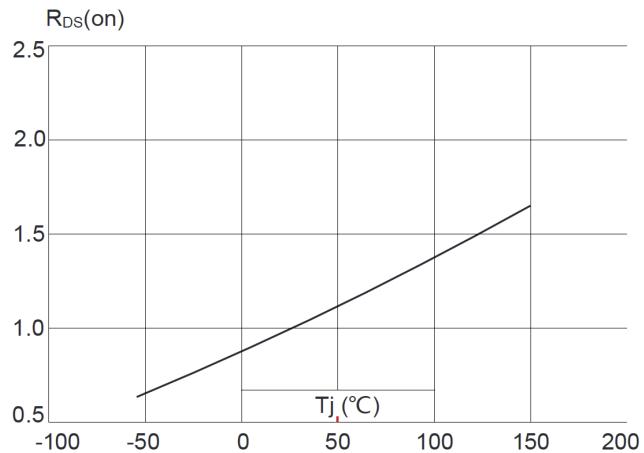


### P-Channel Typical Performance Characteristics

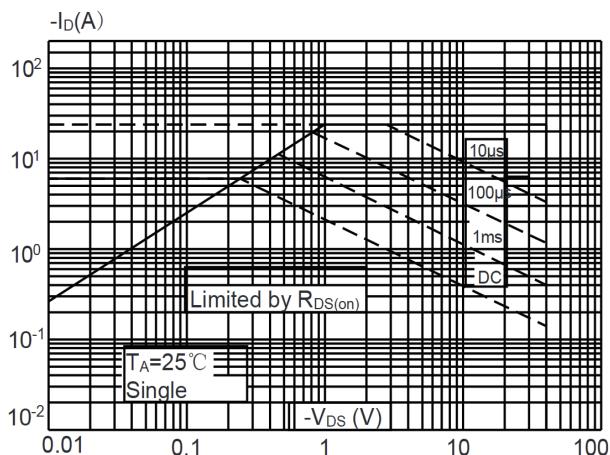
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**



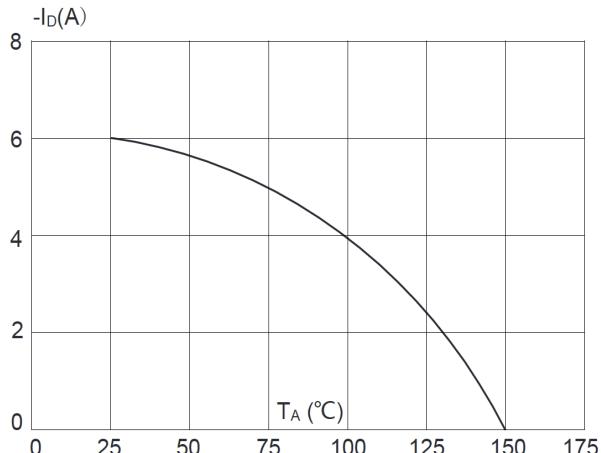
**Figure 8: Normalized on Resistance vs. Junction Temperature**



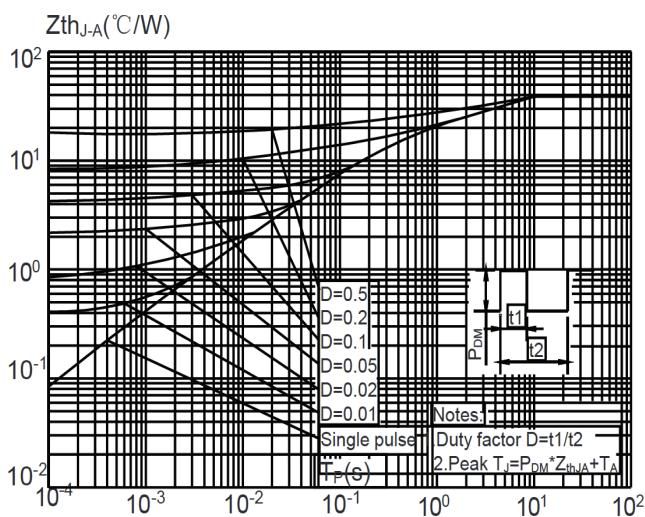
**Figure 9: Maximum Safe Operating Area**



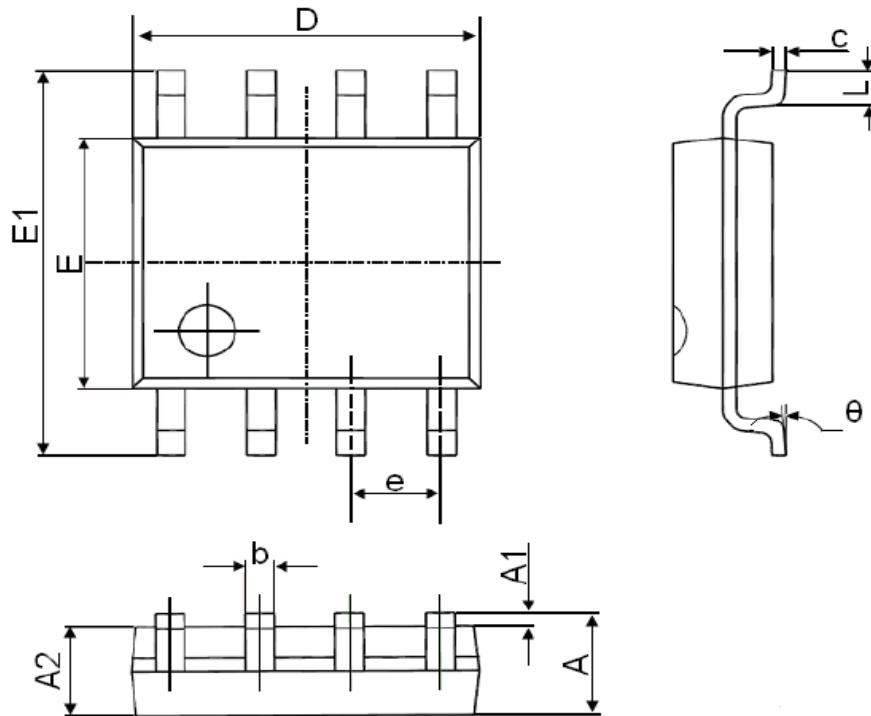
**Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature**



**Figure 11: Maximum Effective Transient Thermal Impedance vs. Duty Factor**



## Package Mechanical Data- SOP-8



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270(BSC)		0.050(BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°